Microscopy TODAY

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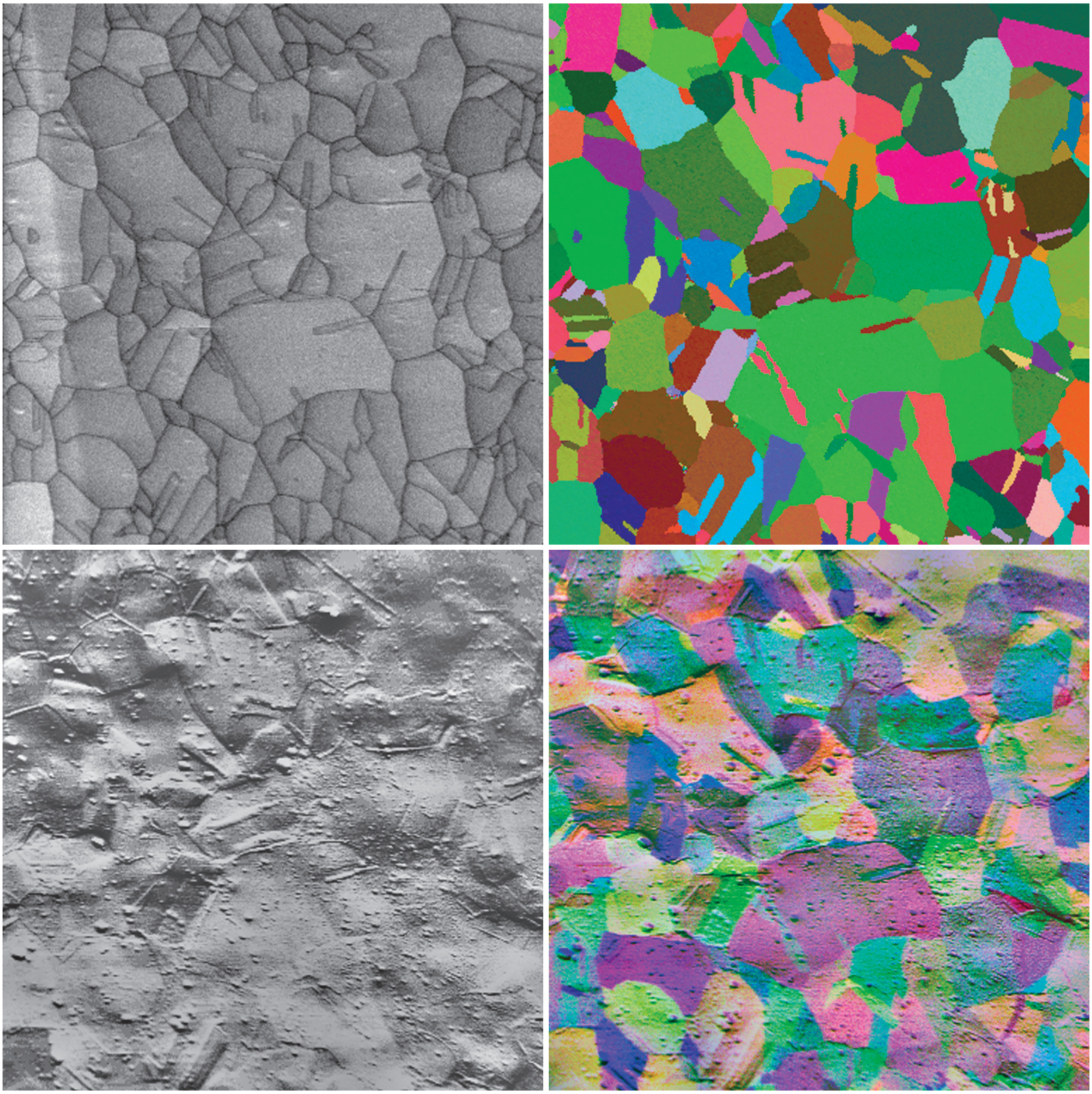

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ASM INTERNATIONAL

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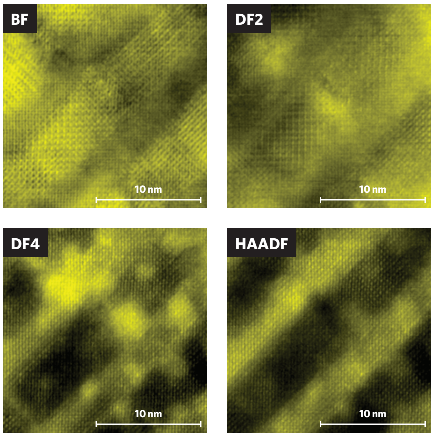
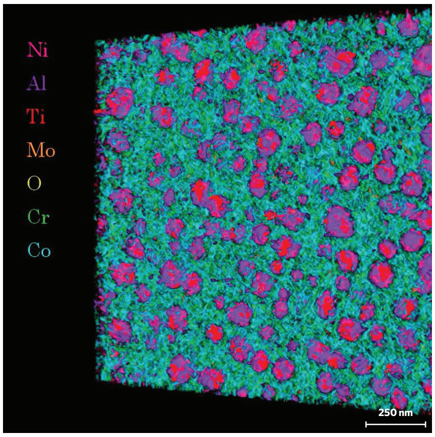
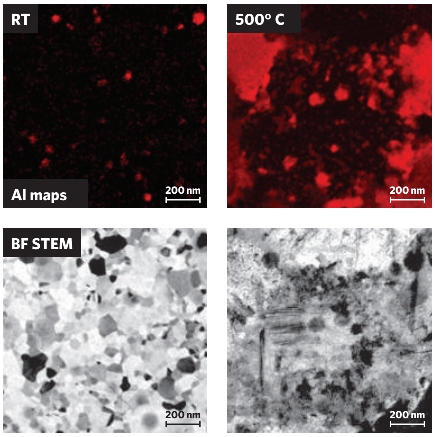


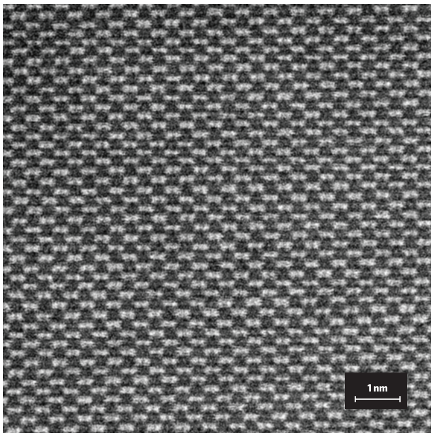
4 channel simultaneous HRSTEM imaging of $SrTiO_3$ using 4 STEM detectors.



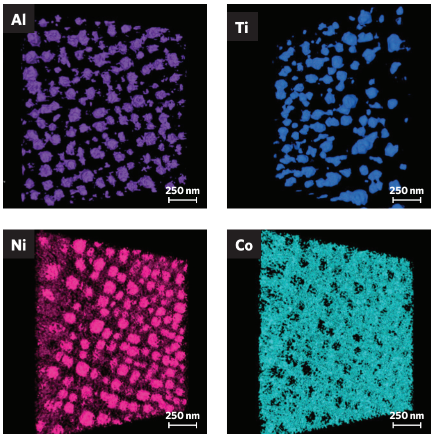
Combined 3D EDS map: Ni, Al, Ti, Mo, Cr, and Co.



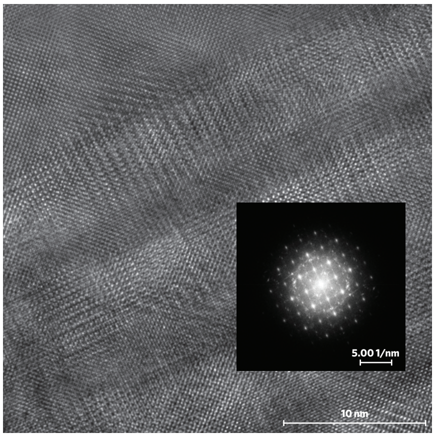
Temperature driven Al aggregation in solar cell. Sample courtesy of Dr. S. Kraschewski, U. Erlangen.



HRSTEM of Si (110) at 200kV.



3D EDS maps at different angles.



HRTEM image of $SrTiO_3$ with Ceta 16M camera.

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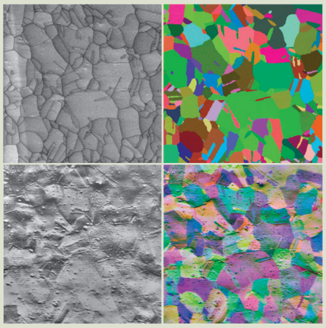

Recrystallized Ni surface imaged with an EBSD detector. Clockwise from top-left: pattern quality image, Euler map, topographical image, and orientation contrast image. Image width = 300 µm.

See article by Schwarzer and Hjelen.

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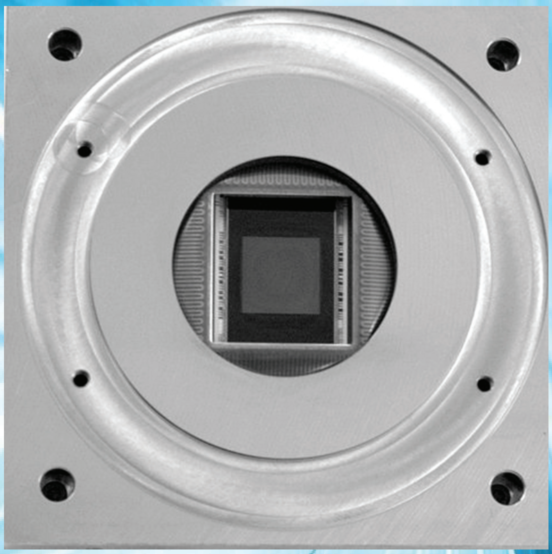
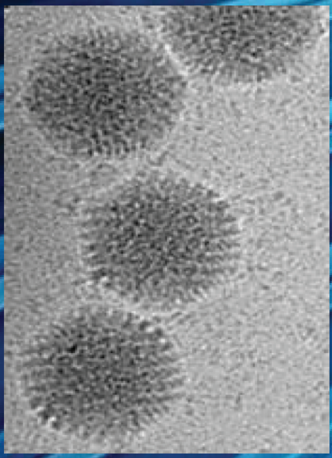
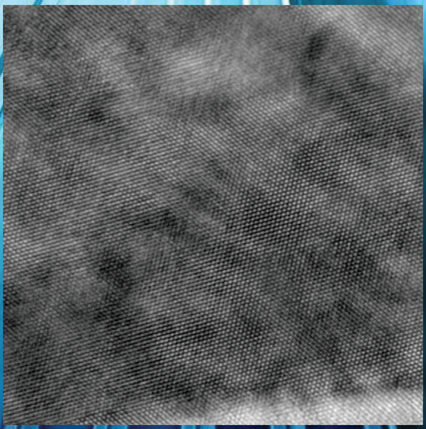




Adenovirus

Dr. Cameron Ackerley
The Hospital for Sick Children

Diffraction



Lattice

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